



## Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-14

CB Certificate No.: 50600326 ITL

Schedule Number: IECQ-L ULTW 16.0003-14-S Rev No.: 1 Revision Date: 2024/08/07 Page 1 of 2

### Appendix-1 (50600326 ITL) Schedule of Scope to Certificate of Approval

| Description test                              | Standard         |
|-----------------------------------------------|------------------|
| Scanning Electron Microscope (SEM)            | T-SEM-3          |
| Energy Dispersive Spectrometry of X-ray (EDS) | T-SEM-3, T-TEM-3 |
| X-Ray imaging                                 | T-EFA-3          |
| Scanning Acoustic Tomography (SAT)            | T-EFA-3          |
| Optical Microscope (OM)                       | T-OMI-3          |
| 3D Optical Microscope (3D OM)                 | T-LAB-3          |
| IC Layout Imaging                             | T-OMI-3          |
| Circuitry analysis                            | T-OMI-3          |
| 3D X-Ray microscope                           | T-EFA-3          |
| Nano Probe                                    | T-EFA-3          |
| Secondary Ion Mass Spectrometry (SIMS)        | T-SIM-3          |
| Atomic Force Microscope (AFM)                 | T-SIM-3          |

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|                                            |         |
|--------------------------------------------|---------|
| Conductive atomic force microscopy (C-AFM) | T-SIM-3 |
| Alpha-step stylus profiler                 | T-SIM-3 |
| X-Ray Photoelectron Spectroscopy (XPS)     | T-SIM-3 |
| Scanning Capacitance Microscopy (SCM)      | T-SIM-3 |

Technical Reviewer of DQS: Paul Yang Date: 8/7/2024

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